

IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

In re Application of

BENOIT R. VEILLETTE

Serial No.

Atty. Docket

US 000295



Filed: CONCURRENTLY

METHOD AND APPARATUS FOR CREATING AND TESTING A CHANNEL DECODER
WITH BUILT-IN-SELF-TEST

Commissioner for Patents
Washington, D.C. 20231

INFORMATION DISCLOSURE STATEMENT UNDER 37 C.F.R. 1.97

Sir:

Enclosed is a Form PTO-1449 and copies of documents listed thereon. These documents are considered to be relevant in that they have been:

- ☒ considered in drafting the specification of the above-referenced application;
- ☒ cited in the specification of the above-referenced application; or
- ☐ cited as an "X" or "Y" document in a foreign Patent Office search report on a foreign counterpart application a copy of which report is also enclosed.

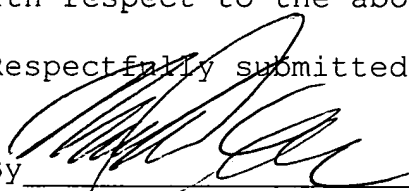
☐ I hereby certify that these documents were cited in said search report not more than three (3) months ago.

☐ Please charge any fee under 1.17(p) for this Information Disclosure Statement to be considered, not exceeding \$240.00, to Account No. 14-1270.

If readily available, English-language counterparts have been substituted for foreign-language patent documents. This disclosure is not an admission that any of these documents is material to or even prior art with respect to the above-referenced application.

Respectfully submitted,

By


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FORM PTO-1449	SERIAL NO.	CASE NO. US000295
LIST OF PATENTS AND PUBLICATIONS FOR APPLICANT'S INFORMATION DISCLOSURE STATEMENT	FILING DATE Concurrently	GROUP ART UNIT
(use several sheets if necessary)	APPLICANT(S): BENOIT R. VEILLETTE	

1c843 U.S. PTO
 09/730659
 12/06/00

REFERENCE DESIGNATION		U.S. PATENT DOCUMENTS				
EXAMINER INITIAL		DOCUMENT NUMBER	DATE	NAME	CLASS/ SUBCLASS	FILING DATE

FOREIGN PATENT DOCUMENTS							
EXAMINER INITIAL		DOCUMENT NUMBER	DATE	COUNTRY	CLASS/ SUBCLASS	TRANSLATION YES NO	

EXAMINER INITIAL	OTHER ART (Including Author, Title, Date, Pertinent Pages, etc.)	
	A1	Article entitled "On-Chip Analog Signal Generation for Mixed-Signal Built-In Self-Test," <i>IEEE Journal of Solid-State Circuits</i> , Vol. 34, No. 3, March 1999, (Authors, Benoit Dufort and Gordon W. Roberts, <i>Member, IEEE</i> , Dated March 1999, pp. 318-330)
	A2	International Test Conference 95 article entitled, "A Built-In Self-Test Strategy for Wireless Communication Systems," Microelectronics And Computer Systems Laboratory, McGill University, Montréal, Quebec, Canada (Authors, Benoit R. Veillette, Gordon W. Roberts, Dated 95, 10 pp.)

EXAMINER	DATE CONSIDERED
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EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609; Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.